

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
						YES	NO
/AW/	2001119451	Apr. 27, 2001	JP			*	
/AW/	2000043652	Feb. 15, 2000	JP			*	
/AW/	6061923	Mar. 4, 1994	JP				
/AW/	10287188	Oct. 27, 1998	JP				
/AW/	2002108381	Apr. 10, 2002	JP			*	

^{*}English language abstract provided.

OTHER DOCUMENTS

EXAMINER	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
INITIAL	

EXAMINER /Andrew Wendell/

DATE CONSIDERED 05/27/2008

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